


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10689336</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>BEAUMONT, MARK</p>
	<p>Examiner</p> <p>Wai, Eric C</p>	<p>Art Unit</p> <p>2195</p>

SEARCHED			
Class	Subclass	Date	Examiner
709	225	07/18/2007	ECW
395	675	07/18/2007	ECW
718	105	07/18/2007	ECW

SEARCH NOTES			
Search Notes		Date	Examiner
Inventor's Name Search		07/18/2007	ECW
East Search		07/18/2007	ECW
Updated East Search		1/18/2008	ECW
Updated East Search to consider references disclosed in IDS 6/2/08		8/6/2008	ECW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
718	105	1/18/2008	ECW